


REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED

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	SHEET	1	2	3	4	5	6	7	8	9	10	11										

PMIC N/A	PREPARED BY <i>Rich C. Offier</i>	DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444		
STANDARDIZED MILITARY DRAWING	CHECKED BY <i>Charles E. Besore</i>	MICROCIRCUITS, LINEAR, PRECISION VOLTAGE REFERENCE, MONOLITHIC SILICON		
	APPROVED BY 	SIZE A	CAGE CODE 67268	5962-89728
	DRAWING APPROVAL DATE 28 DECEMBER 1989	SHEET 1 OF 11		
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DESC FORM 193
SEP 87

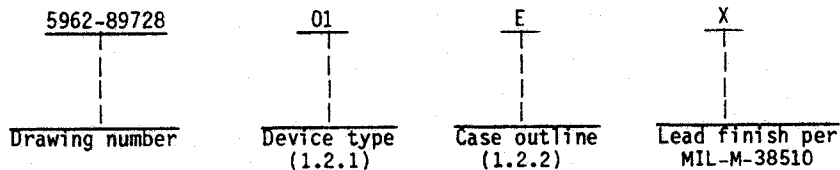
• U.S. GOVERNMENT PRINTING OFFICE: 1987 -- 748-129/60911
5962-E1399

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part number. The complete part number shall be as shown in the following example:



1.2.1 Device types. The device types shall identify the circuit function as follows:

Device type	Generic number	Circuit function
01	AD588S	Pin programmable voltage reference
02	AD588T	Pin programmable voltage reference

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

Outline letter	Case outline
E	D-2 (16-lead, .840" X .310" X .200"), dual-in-line package
2	C-2 (20-terminal, .358" x .358" x .100"), leadless chip carrier package

1.3 Absolute maximum ratings. 1/

Positive supply voltage (V+) - - - - -	+18 V dc
Negative supply voltage (V-) - - - - -	-18 V dc
Storage temperature range - - - - -	-65°C to +150°C
Lead temperature (soldering, 10 seconds) - - - - -	+300°C
Power dissipation at +25°C (P _D) - - - - -	600 mW
Thermal resistance, junction-to-case (θ _{JC}) - - - - -	See MIL-M-38510, appendix C
Thermal resistance, junction-to-ambient (θ _{JA}) - - - - -	90°C/W
Junction temperature (T _J) - - - - -	+175°C

1.4 Recommended operating conditions.

Positive supply voltage (V+) - - - - -	+15 V dc
Negative supply voltage (V-) - - - - -	-15 V dc
Ambient operating temperature range (T _A) - - - - -	-55°C to +125°C

1/ All outputs may be shorted to ground.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A	5962-89728
	REVISION LEVEL	SHEET 2

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Logic diagram. The logic diagram shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I and apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89728
		REVISION LEVEL	SHEET 3

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ -55°C < T _A < +125°C unless otherwise specified	Device type	Group A subgroups	Limits		Unit
					Min	Max	
Output voltage error	V _{OUT}	Outputs: +10 V, -10 V T _A = +25°C	01,02	1	±5.0		mV
			02	12	±3.0		
		Outputs: +5.0 V, -5.0 V T _A = +25°C	01,02	1	±5.0		
			02	12	±3.0		
Symmetry error	S _e	Tracking mode: ±5.0 V T _A = +25°C	A11	1	±1.5		mV
Output voltage drift	dV _O /dT		01	2,3	±6.0		ppm/°C
			02	12	±4.0		
Line regulation	V _{RLN}	2/	A11	1,2,3	±200		μV/V
Load regulation	V _{RLD}	+10 V output, 0 mA ≤ I _{OUT} ≤ 10 mA	A11	1,2,3	±50		μV/mA
		-10 V output, -10 mA ≤ I _{OUT} ≤ 0 mA	A11				
Supply current	I _{CC}		A11	1,2,3	10		mA
Output current	I _{OUT}	Amplifiers A3, A4 3/	A11	1,2,3	-10	+10	mA

1/ Unless otherwise specified, V⁺ = 15 V dc, V⁻ = -15 V dc. Test conditions using +10 V output, +5.0 V and -5.0 V outputs, and -10 V output, with ±5.0 V tracking are as specified on figure 3.

2/ Test conditions:

+10 V output	V ⁻ = -15 V dc, 13.5 V dc ≤ V ⁺ ≤ 18 V dc
-10 V output	-18 V dc ≤ V ⁻ ≤ -13.5 V dc, V ⁺ = 15 V dc
±5.0 V output	V ⁺ = 18 V dc, V ⁻ = -10.8 V dc
	V ⁺ = +10.8 V dc, V ⁻ = -10.8 V dc

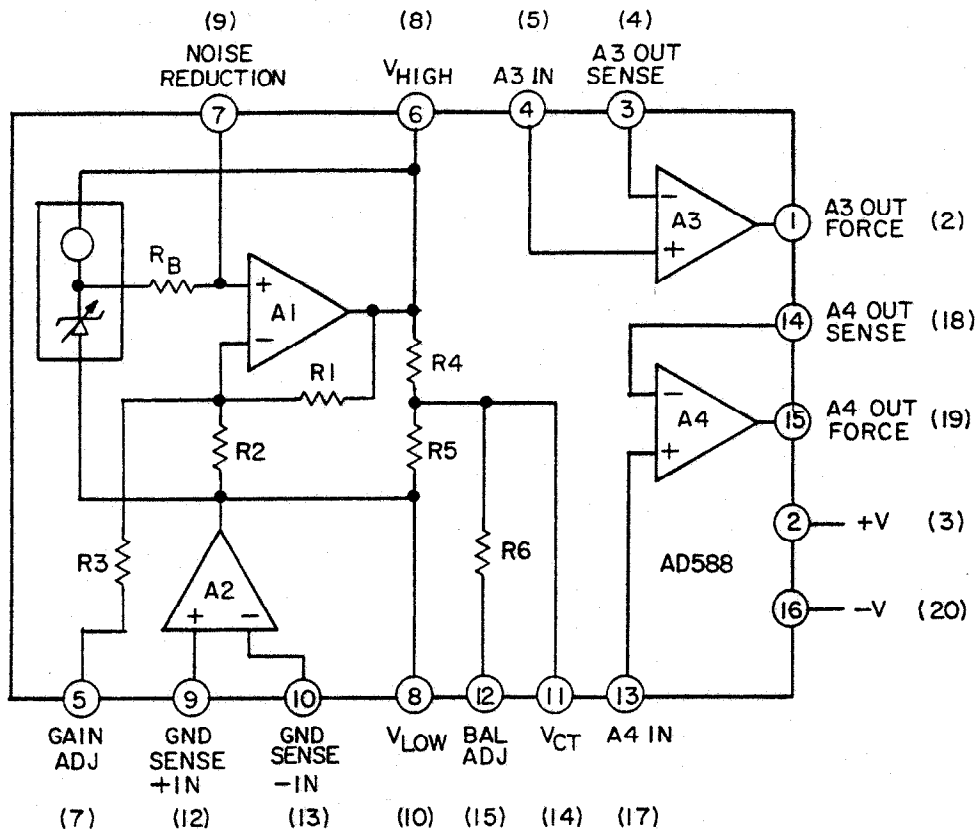
3/ Parameters shall be tested as part of device initial characterization and after design and process change. Parameter shall be guaranteed to the limits specified in table I for all lots not specifically tested.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A	5962-89728
	REVISION LEVEL	SHEET 4

Device types	01 and 02	
Case outlines	E	2
Terminal number	Terminal symbol	
1	A3 OUT FORCE	NC
2	+V	A3 OUT FORCE
3	A3 OUT SENSE	+V
4	A3 +IN	A3 OUT SENSE
5	GAIN ADJ	A3 +IN
6	V _{HIGH}	NC
7	NOISE REDUCTION	GAIN ADJ
8	V _{LOW}	V _{HIGH}
9	GND SENSE +IN	NOISE REDUCTION
10	GND SENSE -IN	V _{LOW}
11	V _{CT}	NC
12	BAL ADJ	GND SENSE +IN
13	A4 +IN	GND SENSE -IN
14	A4 OUT SENSE	V _{CT}
15	A4 OUT FORCE	BAL ADJ
16	-V	NC
17	---	A4 +IN
18	---	A4 OUT SENSE
19	---	A4 OUT FORCE
20	---	-V

FIGURE 1. Terminal connections.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89728
		REVISION LEVEL	SHEET 5



NOTE: Terminal numbers within the parentheses symbol represent the case 2 package.

FIGURE 2. Logic diagram.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A	5962-89728
	REVISION LEVEL	SHEET 6

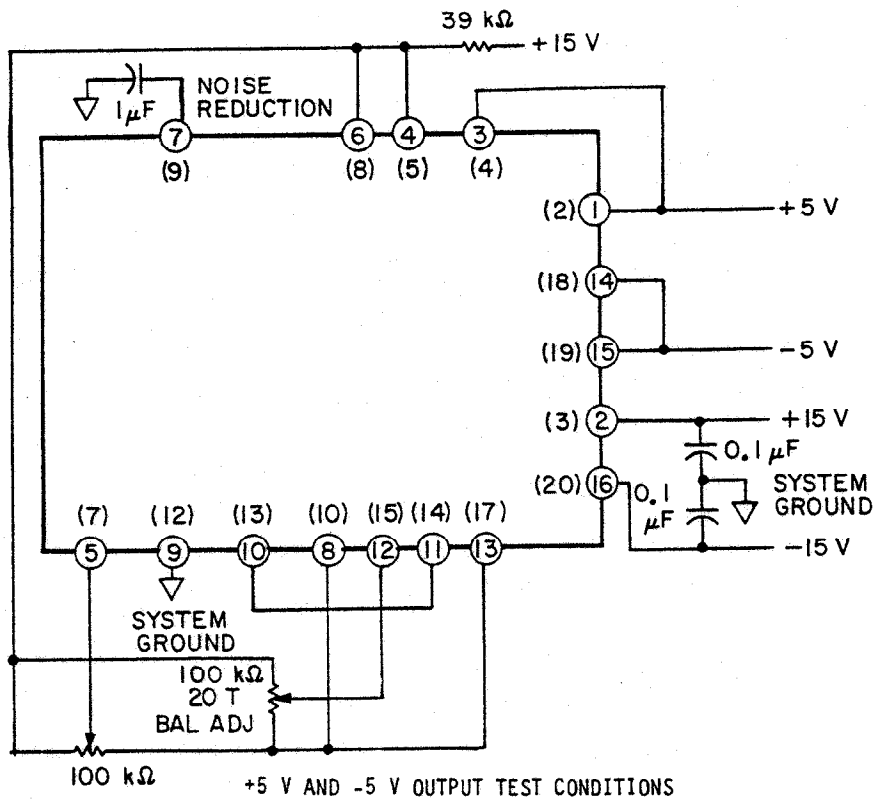
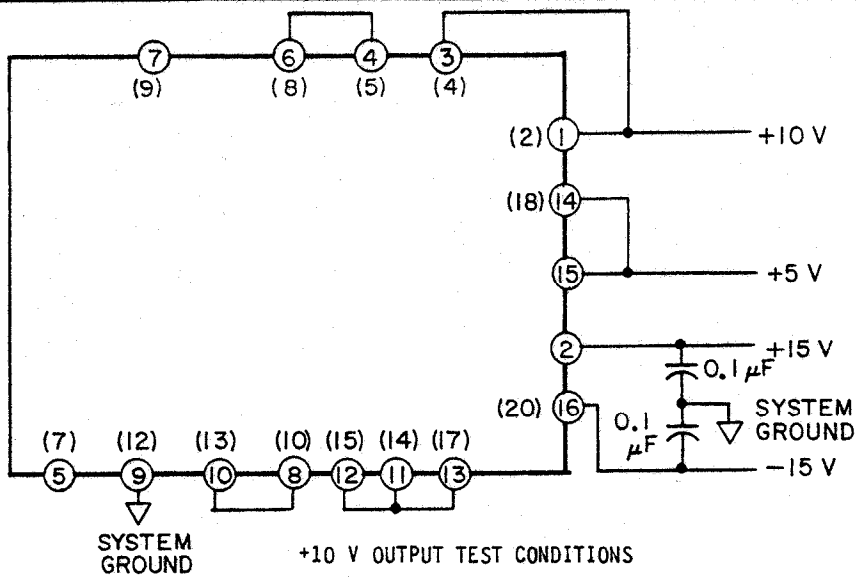


FIGURE 3. Test conditions.

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DEFENSE ELECTRONICS SUPPLY CENTER
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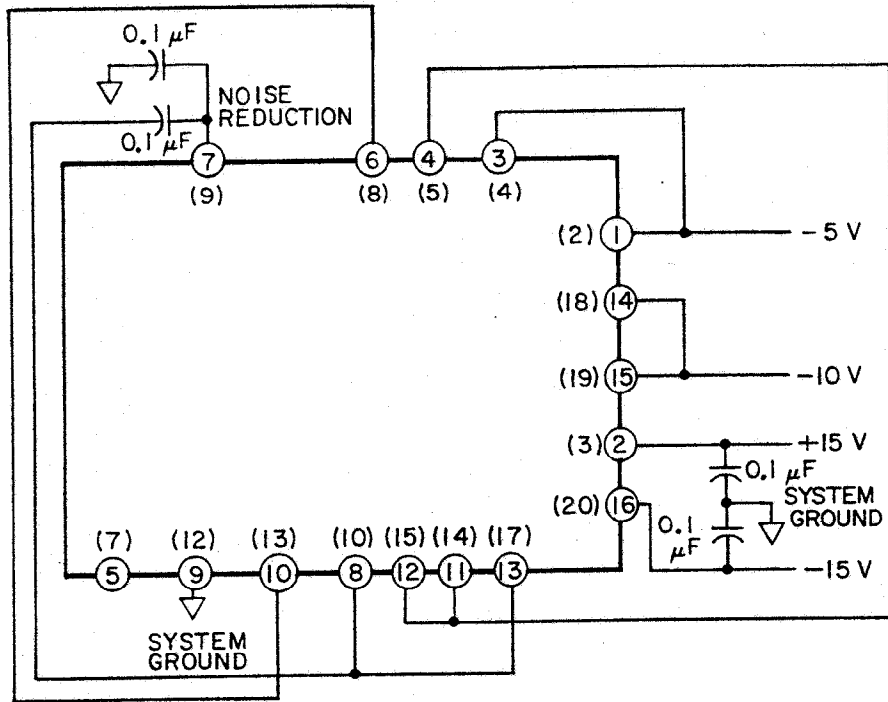
SIZE
A

5962-89728

REVISION LEVEL

SHEET

7



-10 V OUTPUT TEST CONDITIONS

NOTE: Terminal numbers within the parentheses symbol represent the case 2 package.

FIGURE 3. Test conditions - Continued.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A		5962-89728
		REVISION LEVEL	SHEET 8

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^{\circ}\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.
- c. Subgroup 12 test is used for grading and part selection at $T_A = +25^{\circ}\text{C}$.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 4, 5, 6, 7, 8, 9, 10, and 11 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 12 test is used for grading and part selection at $T_A = +25^{\circ}\text{C}$.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A	5962-89728
	REVISION LEVEL	SHEET 9

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1
Final electrical test parameters (method 5004)	1*,2,3,12
Group A test requirements (method 5005)	1,2,3,12
Group C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions; method 1005 of MIL-STD-883:
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

STANDARDIZED MILITARY DRAWING DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE A	5962-89728	
		REVISION LEVEL	SHEET 10

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of the drawings covering microelectronics devices (FSC 5962) should contract DESC-ECS telephone (513) 296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved source of supply listed below is for information purposes only and is current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number 1/	Replacement military specification part number
5962-8972801EX	24355	AD588SD/883B	---
5962-89728012X	24355	AD588SE/883B	---
5962-8972802EX	24355	AD588TD/883B	---
5962-89728022X	24355	AD588TE/883B	---

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

Vendor CAGE number

24355

Vendor name and address

Analog Devices, Incorporated
 Route 1 Industrial Park
 P. O. Box 9106
 Norwood, MA 02062
 Point of contact: 804 Woburn Street
 Wilmington, MA 01887

**STANDARDIZED
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DEFENSE ELECTRONICS SUPPLY CENTER
 DAYTON, OHIO 45444

SIZE
A

5962-89728

REVISION LEVEL

SHEET

11